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PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Andre BELMONT, Laurent ROBERT, Abdel Nacer AIT
MANI

Application No.: New U.S. National Stage of
PCT/FR01/02411

Filed: March 11, 2002

Docket No.: 112183

For: METHOD FOR MAKING A CARD WITH MULTIPLE CONTACT TIPS FOR
TESTING MICROSPHERE INTEGRATED CIRCUITS, AND TESTING DEVICE
USING SAID CARD

PRELIMINARY AMENDMENT

Director of the U.S. Patent and Trademark Office
Washington, D. C. 20231

Sir:

Prior to initial examination, please amend the above-identified application as follows:

IN THE CLAIMS:

Please replace claims 6 and 9 as follows:

6. (Amended) A card with multiple tips obtained according to the process of
claim 1.

9. (Amended) The card with multiple tips according to claim 7, wherein the
truncated part (30c) of the support part (30) is provided with a window (38) equipped with a
plate made of transparent material, glass or quartz, allowing visual testing of the alignment of
the tips (26) on the connection pads (50) of the semi-conductor chip (52).

Please add new claims 10-14 as follows:

--10. A card with multiple tips obtained according to the process of claim 2.--